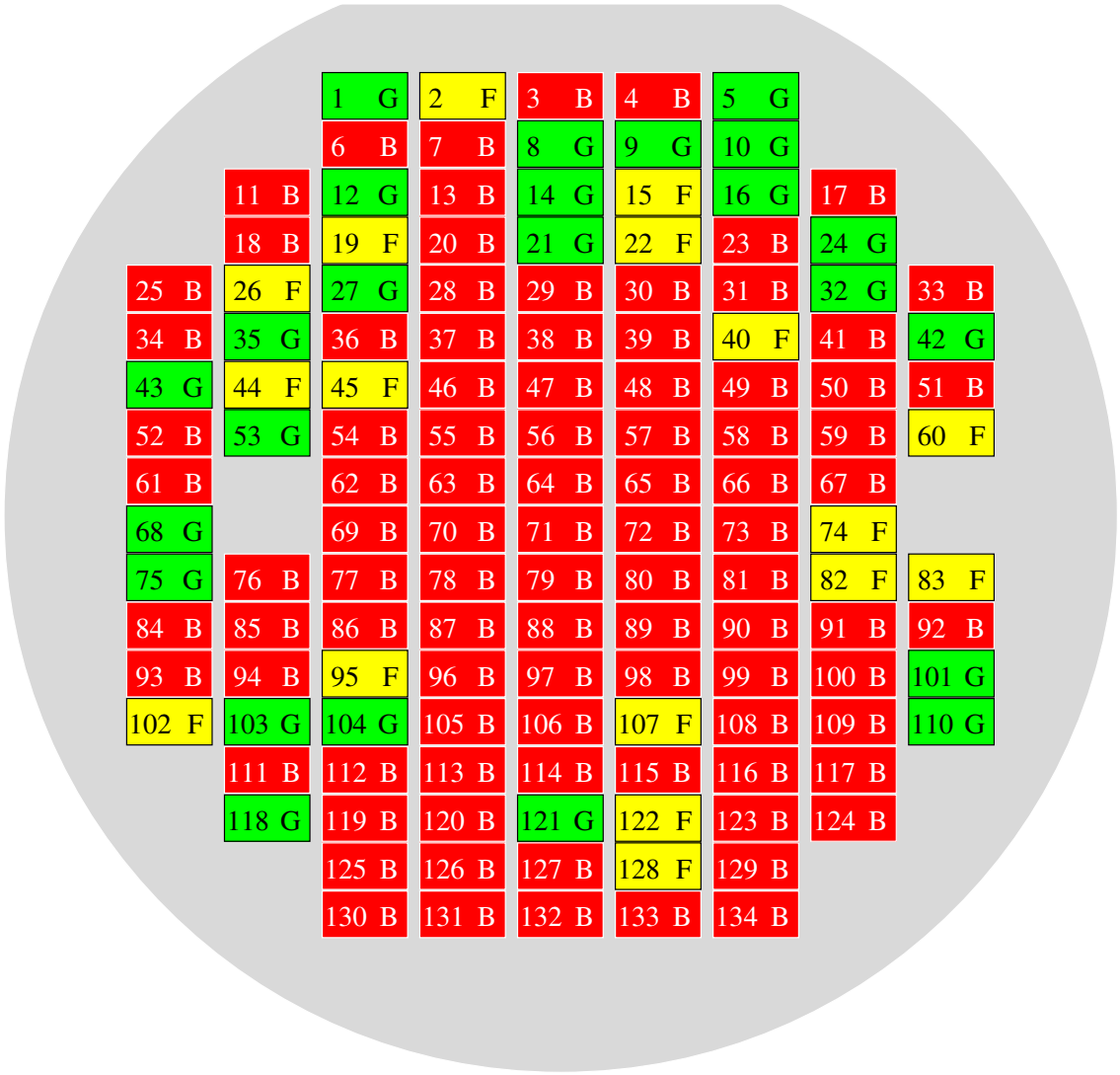
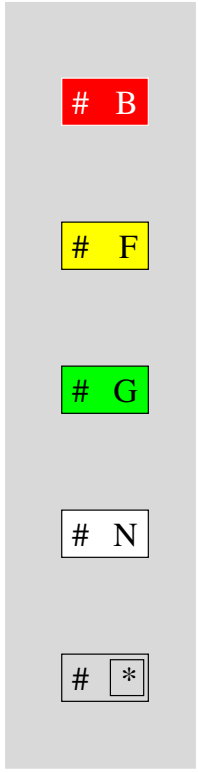
Die quality map for wafer 80 s/n: Y21316-12-15 (annealed)

Date: 04/01/99





Bad die

Fair die

Good die

No info

Manually tagged